

HiPerFET™ **Power MOSFETs**

N-Channel Enhancement Mode

IXFH/IXFM42N20 IXFH/IXFM/IXFT50N20 IXFH/IXFT58N20

$\mathbf{V}_{ exttt{DSS}}$	I _{D25}	$\mathbf{R}_{DS(on)}$
200 V	42 A	$60 \mathrm{m}\Omega$
200 V	50 A	45m $Ω$
200 V	58 A	40m $Ω$

 $t_{rr} \leq 200 \text{ ns}$

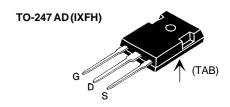
High dv/dt, Low t_{rr}, HDMOS™ Family Obsolete: IXFM42N20 IXFM50N20



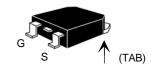
Symbol	Test Conditions		Maximun	n Ratings
V _{DSS}	$T_{J} = 25^{\circ}C \text{ to } 150^{\circ}C$		200	V
\mathbf{V}_{DGR}	$T_J = 25^{\circ}C$ to $150^{\circ}C$; $R_{GS} = 1 M\Omega$		200	V
V _{GS}	Continuous		±20	V
V _{GSM}	Transient		±30	V
I _{D25}	T _C = 25°C	42N20 50N20 58N20	42 50 58	A A A
I _{DM}	$T_{\rm C} = 25^{\circ}$ C, pulse width limited by $T_{\rm JM}$	42N20 50N20 58N20	168 200 232	A A A
I _{AR}	$T_{c} = 25^{\circ}C$	42N20 50N20 58N20	42 50 58	A A A
E _{AR}	T _C = 25°C		30	mJ
dv/dt	$\begin{split} &I_{_{S}} \leq I_{_{DM}}, di/dt \leq 100 A/\mu s, V_{_{DD}} \leq V_{_{DSS}}, \\ &T_{_{J}} \leq 150^{\circ}C, R_{_{G}} = 2 \Omega \end{split}$		5	V/ns
$\overline{\mathbf{P}_{\scriptscriptstyle \mathrm{D}}}$	T _C = 25°C		300	W
T _J			-55 +150	°C
T_{JM}			150	°C
T_{stg}			-55 +150	°C
T _L	1.6 mm (0.062 in.) from case for 10 s		300	°C
M _d	Mountingtorque		1.13/10	Nm/lb.in.
Weight		TO-204	= 18 g, TO-	247 = 6 g

Symbol	Symbol rest Conditions			ratings
V _{DSS}	$T_{_{\rm J}} = 25^{\circ}\text{C} \text{ to } 150^{\circ}\text{C}$		200	V
V _{DGR}	$T_J = 25^{\circ}C$ to $150^{\circ}C$; $R_{GS} = 1 M\Omega$		200	V
V _{GS}	Continuous		±20	V
V _{GSM}	Transient		±30	V
I _{D25}	T _c = 25°C	42N20	42	A
220		50N20	50	Α
		58N20	58	Α
I _{DM}	$T_{c} = 25^{\circ}C$, pulse width limited by $T_{.IM}$	42N20	168	Α
	-	50N20	200	Α
		58N20	232	Α
I _{AR}	$T_{c} = 25^{\circ}C$	42N20	42	Α
	ū	50N20	50	Α
		58N20	58	Α
E _{AR}	T _C = 25°C		30	mJ
dv/dt	$\begin{split} I_{S} &\leq I_{DM}, di/dt \leq 100 \text{A/}\mu\text{s}, V_{DD} \leq V_{DSS}, \\ T_{J} \leq 150^{\circ}\text{C}, R_{G} = 2 \Omega \end{split}$		5	V/ns
P_{D}	T _C = 25°C		300	W
T			-55 +150	°C
\mathbf{T}_{JM}			150	°C
T _{stg}			-55 + 150	°C
T _L	1.6 mm (0.062 in.) from case for 10 s		300	°C
$\overline{\mathbf{M}_{d}}$	Mountingtorque		1.13/10	Nm/lb.in.

Symbol	Test Conditions	(T _J = 25°C, unle m		 ristic Va se spec max.	
V _{DSS}	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	2	200		V
V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 4 \text{ mA}$		2	4	V
I _{GSS}	$V_{GS} = \pm 20 V_{DC}, V_{DS} = 0$			±100	nA
I _{DSS}	$V_{DS} = 0.8 \bullet V_{DSS}$ $V_{GS} = 0 V$	T _J = 25°C T _J = 125°C		200 1	μA mA



TO-268 (D3) Case Style



TO-204 AE (IXFM) Package unavailable



G = Gate, D = Drain, S = Source,TAB = Drain

Features

- International standard packages
- Low R_{DS (on)} HDMOS™ process
 Rugged polysilicon gate cell structure
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
 - easy to drive and to protect
- Fast intrinsic Rectifier

Applications

- · DC-DC converters
- Synchronous rectification
- · Battery chargers
- Switched-mode and resonant-mode power supplies
- DC choppers
- · AC motor control
- · Temperature and lighting controls
- · Low voltage relays

Advantages

- Easy to mount with 1 screw (TO-247) (isolated mounting screw hole)
- High power surface mountable package
- · High power density

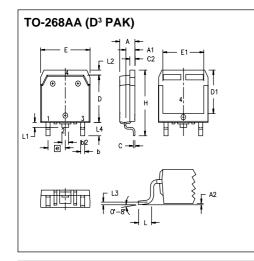
91522H (2/98)

Symbol	Test Conditions	С	haracte	ristic V	/alues
$(T_J = 25^\circ)$	C, unless otherwise specified)	Min.	Тур.	Ma	ax.
R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_{D} = 0.5 I_{D25}$ 42N20 50N20 58N20			0.06 0.04 0.04	Ι5 Ω
	Pulse test, $t \le 300~\mu s$, duty cycle $d \le 2~\%$				
\mathbf{g}_{fs}	$V_{DS} = 10 \text{ V}; I_{D} = 0.5 I_{D25}, \text{ pulse test}$	20	32		S
C _{iss} C _{oss} C _{rss}	$ V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz} $		4400 800 285		pF pF pF
t _{d(on)} t _r t _{d(off)}	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \text{ V}_{DSS}, I_{D} = 0.5 \text{ I}_{D25}$ $R_{G} = 1 \Omega \text{ (External)}$		18 15 72 16	25 20 90 25	ns ns ns
Q _{g(on)} Q _{gs} Q _{gd}	$ V_{GS} = 10 \text{ V}, V_{DS} = 0.5 V_{DSS}, I_{D} = 0.5 I_{D25} $		190 35 95	220 50 110	nC nC nC
R _{thJC}	(TO-247 and TO-204 Case styles)		0.25	0.42	K/W K/W

Source-Drain Diode

Characteristic Values (T = 25°C, unless otherwise specified)

		(1 _{.1} = 20 0, unicoo	Oth ICI W	oc spcc	mca,
Symbol	Test Conditions	Min.	Тур.	Max.	
I _s	$V_{GS} = 0 V$	42N20 50N20		42 50	A A
		58N20		58	Α
I _{sm}	Repetitive;	42N20		168	Α
	pulse width limited by T	50N20		200	Α
	· Jivi	58N20		232	Α
V _{SD}	$I_F = I_S$, $V_{GS} = 0 \text{ V}$, Pulse test, $t \le 300 \mu\text{s}$, duty cycle	ed≤2%		1.5	V
t _{rr})	T _J = 25°C		200	ns
	$I_F = 25A$,	$T_{J} = 125^{\circ}C$		300	ns
\mathbf{Q}_{RM}	$-di/dt = 100 A/\mu s$,	T ₁ = 25°C	1.5		μС
'RM	$V_R = 100 \text{ V}$	T _J = 125°C	2.6		μC
I _{RM}		$T_{J} = 25^{\circ}C$	19		Α
ر)	T = 125°C	23		Α



Dim.	Millimeter Inches		nes	
	Min.	Max.	Min.	Max.
Α	4.9	5.1	.193	.201
A ₁	2.7	2.9	.106	.114
A_2	.02	.25	.001	.010
b	1.15	1.45	.045	.057
b_2	1.9	2.1	.75	.83
С	.4	.65	.016	.026
D	13.80	14.00	.543	.551
Ε	15.85	16.05	.624	.632
Εı	13.3	13.6	.524	.535
е	5.45	BSC	.21	5 BSC
Н	18.70	19.10	.736	.752
L	2.40	2.70	.094	.106
L1	1.20	1.40	.047	.055
L2	1.00	1.15	.039	.045
L3	0.25	5 BSC	.010	BSC
L4	3.80	4.10	.150	.161

TO-247 AD (IXFH) Outline - N Dim. Millimeter Inches Min. Max. Min. Max. 0.780 0.800 19.81 20.32 В 20.80 21.46 0.819 0.845 С 15.75 16.26 0.610 0.640 3.55 3.65 0.140 0.144 Е 4.32 5.49 0.170 0.216 F 0.212 0.244 5.4 6.2 G 1.65 2.13 0.065 0.084 Н 4.5 0.177 J 1.0 1.4 0.040 0.055 K 10.8 11.0 0.426 0.433

5.3

8.0

4.7

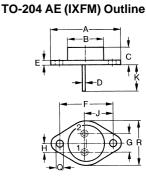
0.4

1.5 2.49

0.185 0.209

 $0.016 \ 0.031$

0.087 0.102



L

M

Ν

Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	38.61	39.12	1.520	1.540
B	-	22.22		0.875
C D		11.40 1.60	0.252 0.057	
E	1.52	3.43	0.060	0.135
F	30.15	BSC	1.187	BSC
G	10.67	11.17	0.420	0.440
H	5.21	5.71	0.205	0.225
J		17.14	0.655	0.675
K		12.19	0.440	0.480
Q		4.19	0.151	0.165
R		26.66	0.991	1.050

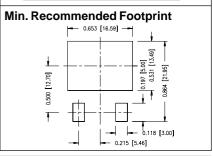


Fig. 1 Output Characteristics

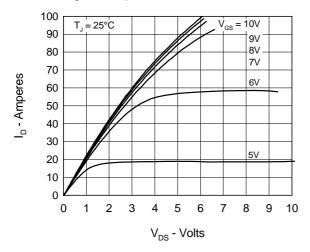


Fig. 3 $R_{DS(on)}$ vs. Drain Current

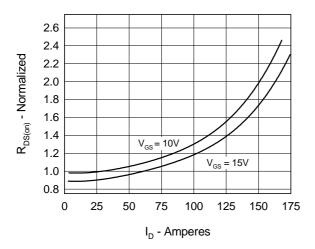


Fig. 5 Drain Current vs.

Case Temperature

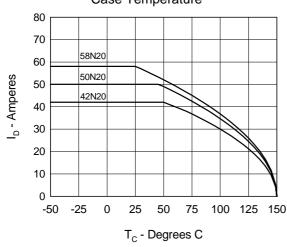


Fig. 2 Input Admittance

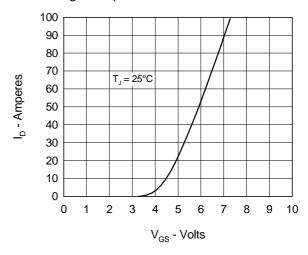


Fig. 4 Temperature Dependence

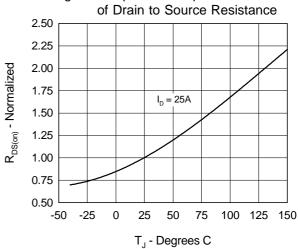


Fig. 6 Temperature Dependence of Breakdown and Threshold Voltage

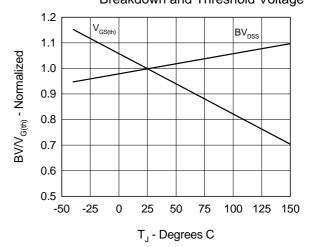


Fig.7 Gate Charge Characteristic Curve

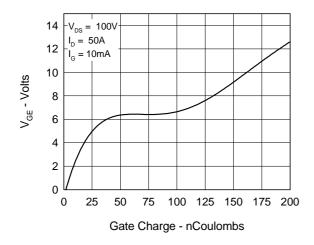


Fig.9 Capacitance Curves

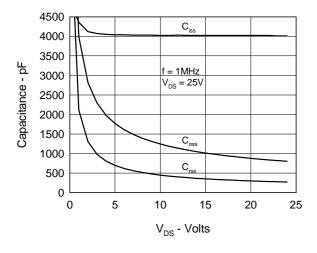


Fig.11 Transient Thermal Impedance

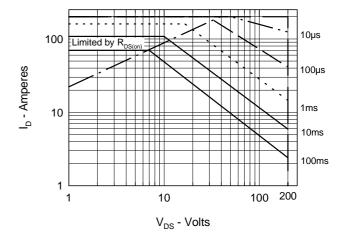
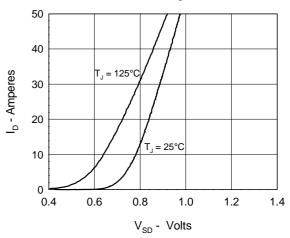
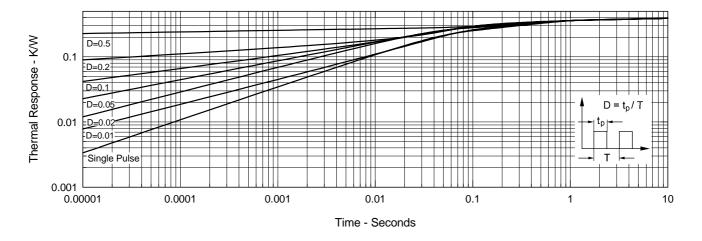


Fig.8 Forward Bias Safe Operating Area

Fig.10 Source Current vs. Source to Drain Voltage





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